Horizontal Deflection Transistor

- ... designed for use in televisions.
- Collector-Emitter Voltages VCES 1500 Volts
- Fast Switching 400 ns Typical Fall Time
- Low Thermal Resistance 1°C/W Increased Reliability
- Glass Passivated (Patented Photoglass). Triple Diffused Mesa Technology for Long Term Stability

BU208A

5.0 AMPERES NPN SILICON POWER TRANSISTOR 700 VOLTS



CASE 1-07 TO-204AA (TO-3)

MAXIMUM RATINGS

Rating	Symbol	BU208A	Unit
Collector–Emitter Voltage	VCEO(sus)	700	Vdc
Collector–Emitter Voltage	VCES	1500	Vdc
Emitter-Base Voltage	V _{EB}	5.0	Vdc
Collector Current — Continuous — Peak	I _C	5.0 7.5	Vdc
Base Current — Continuous — Peak (Negative)	I _B	4.0 3.5	Adc
Total Power Dissipation @ T _C = 95°C Derate above 95°C	PD	12.5 0.625	Watts W/°C
Operating and Storage Junction Temperature Range	TJ, T _{stg}	-65 to +115	°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{ heta JC}$	1.6	°C/W
Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	TL	275	°C

NOTES:

- 1. Pulsed 5.0 ms, Duty Cycle \leq 10%.
- 2. See page 3 for Additional Ratings on A Type.
- 3. Figures in () are Standard Ratings Motorola Guarantees are Superior.

BU208A

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•		•			
Collector–Emitter Sustaining Voltage (I _C = 100 mAdc, L = 25 mH)		VCEO(sus)	700	_	_	Vdc
Collector Cutoff Current ¹ A (V _{CE} = rated V _{CES} , V _{BE} = 0)	LL TYPES	ICES	_	_	1.0	mAdc
Emitter Base Voltage ¹ (I _C = 0, I _E = 10 mAdc) (I _C = 0, I _E = 100 mAdc)		V _{EBO}	5 —	- 7	_ _	Vdc
ON CHARACTERISTICS ¹	•		•			•
DC Current Gain (I _C = 4.5 Adc, V _{CE} = 5 Vdc)		hFE	2.25	_	_	
Collector–Emitter Saturation Voltage (I _C = 4.5 Adc, I _B = 2 Adc)		VCE(sat)	_	_	1	Vdc
Base–Emitter Saturation Voltage (I _C = 4.5 Adc, I _B = 2 Adc)		V _{BE(sat)}	_	_	1.5	Vdc
DYNAMIC CHARACTERISTICS			•			
Current–Gain Bandwidth Product (I _C = 0.1 Adc, V _{CE} = 5 Vdc, f _{test} = 1 MHz)		f _T	_	4	_	MHz
Output Capacitance (V _{CB} = 10 Vdc, I _E = 0, f _{test} = 1 MHz)		C _{ob}	_	125	_	pF
SWITCHING CHARACTERISTICS	•					
Storage Time (see test circuit fig. 1) (I _C = 4.5 Adc, I _{B1} = 1.8 Adc, L _B = 10 μ H)		t _S	_	8	_	μs
Fall time (see test circuit fig. 1) (I _C = 4.5 Adc, I _{B1} = 1.8 Adc, L _B = 10 μ H)		tf	_	0.4	_	μs

¹Pulse test: PW = 300 μ s; Duty cycle \leq 2%.

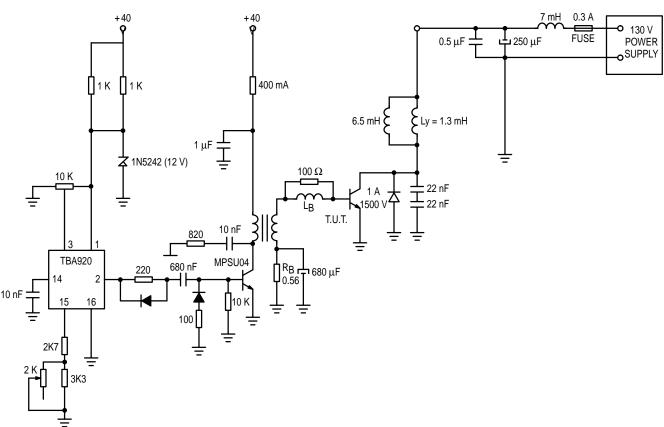


Figure 1. Switching Time Test Circuit

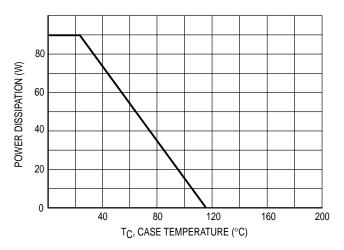


Figure 2. Power Derating

BASE DRIVE The Key to Performance

By now, the concept of controlling the shape of the turn–off base current is widely accepted and applied in horizontal deflection design. The problem stems from the fact that good saturation of the output device, prior to turn–off, must be assured. This is accomplished by providing more than enough IB1 to satisfy the lowest gain output device hFE at the end of scan ICM. Worst–case component variations and maximum high voltage loading must also be taken into account.

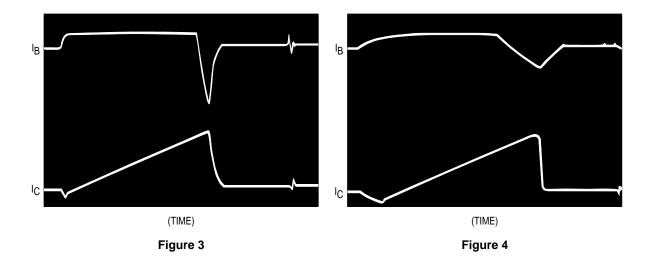
If the base of the output transistor is driven by a very low impedance source, the turn-off base current will reverse very quickly as shown in Fig. 3. This results in rapid, but only partial collector turn-off, because excess carriers become trapped in the high resistivity collector and the transistor is still conductive. This is a high dissipation mode, since the collector voltage is rising very rapidly. The problem is overcome by adding inductance to the base circuit to slow the base current reversal as shown in Fig. 4, thus allowing access carrier recombination in the collector to occur while the base current is still flowing.

Choosing the right L_B Is usually done empirically since the equivalent circuit is complex, and since there are several important variables (I_{CM}, I_{B1}, and h_{FE} at I_{CM}). One method is to plot fall time as a function of L_B, at the desired conditions, for several devices within the h_{FE} specification. A more informative method is to plot power dissipation versus I_{B1} for a range of values of L_B.

This shows the parameter that really matters, dissipation, whether caused by switching or by saturation. For very low LB a very narrow optimum is obtained. This occurs when IB1 hFE ≅ ICM, and therefore would be acceptable only for the "typical" device with constant ICM. As LB is increased, the curves become broader and flatter above the IB1. hFE = ICM point as the turn off "tails" are brought under control. Eventually, if LB is raised too far, the dissipation all across the curve will rise, due to poor initiation of switching rather than tailing. Plotting this type of curve family for devices of different hff, essentially moves the curves to the left, or right according to the relation I_{B1} h_{FE} = constant. It then becomes obvious that, for a specified ICM, an LB can be chosen which will give low dissipation over a range of hFE and/or lB1. The only remaining decision is to pick IB1 high enough to accommodate the lowest hff part specified. Neither LB nor IB1 are absolutely critical. Due to the high gain of Motorola devices it is suggested that in general a low value of IB1 be used to obtain optimum efficiency — eg. for BU208A with $I_{CM} = 4.5$ A use $I_{B1} \approx 1.5 \text{ A}$, at $I_{CM} = 4 \text{ A}$ use $I_{B1} \approx 1.2 \text{ A}$. These values are lower than for most competition devices but practical tests have showed comparable efficiency for Motorola devices even at the higher level of IB1.

An LB of 10 μ H to 12 μ H should give satisfactory operation of BU208A with ICM of 4 to 4.5 A and IB1 between 1.2 and 2 A.

TEST CIRCUIT WAVEFORMS



TEST CIRCUIT OPTIMIZATION

The test circuit may be used to evaluate devices in the conventional manner, i.e., to measure fall time, storage time, and saturation voltage. However, this circuit was designed to evaluate devices by a simple criterion, power supply input.

Excessive power input can be caused by a variety of problems, but it is the dissipation in the transistor that is of fundamental importance. Once the required transistor operating current is determined, fixed circuit values may be selected.

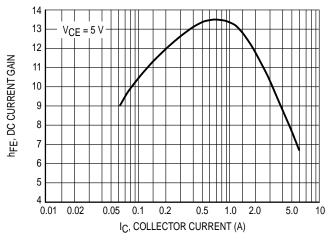


Figure 5. DC Current Gain

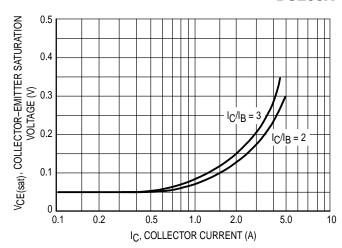


Figure 6. Collector-Emitter Saturation Voltage

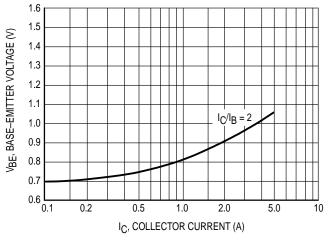


Figure 7. Base-Emitter Saturation Voltage

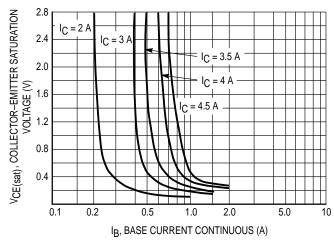


Figure 8. Collector Saturation Region

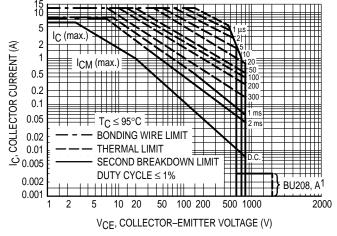
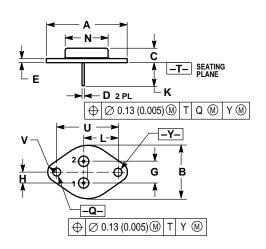


Figure 9. Maximum Forward Bias Safe Operating Area

¹Pulse width \leq 20 μ s. Duty cycle \leq 0.25. R_{BE} \leq 100 Ohms.

PACKAGE DIMENSIONS



NOTES

- DIMENSIONING AND TOLERANCING PER ANSI
 VALSE MARKET
- Y14.5M, 1982.
 2. CONTROLLING DIMENSION: INCH.
- ALL RULES AND NOTES ASSOCIATED WITH
 REFERENCED TO-204AA OUTLINE SHALL APPLY.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	1.550 REF		39.37 REF		
В		1.050		26.67	
С	0.250	0.335	6.35	8.51	
D	0.038	0.043	0.97	1.09	
Е	0.055	0.070	1.40	1.77	
G	0.430 BSC		10.92 BSC		
Н	0.215 BSC		5.46 BSC		
K	0.440	0.480	11.18	12.19	
L	0.665	BSC	16.89 BSC		
N		0.830		21.08	
ø	0.151	0.165	3.84	4.19	
U	1.187 BSC		30.15 BSC		
V	0.131	0.188	3.33	4 77	

STYLE 1: PIN 1. BASE 2. EMITTER CASE: COLLECTOR

CASE 1-07 TO-204AA (TO-3) ISSUE Z

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